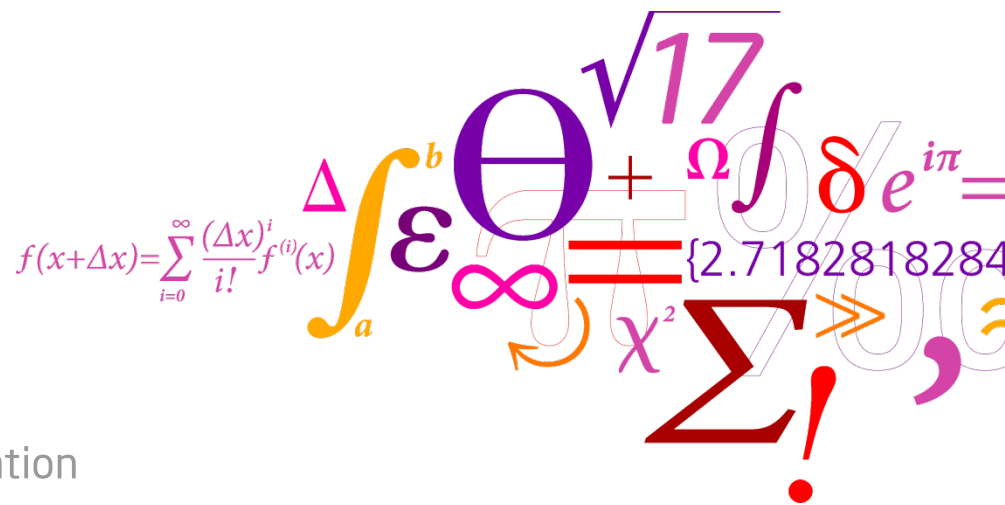


# AFM Icon Re-training

Marts 26th 2015

April 15th 2015



DTU Danchip

National Center for Micro- and Nanofabrication

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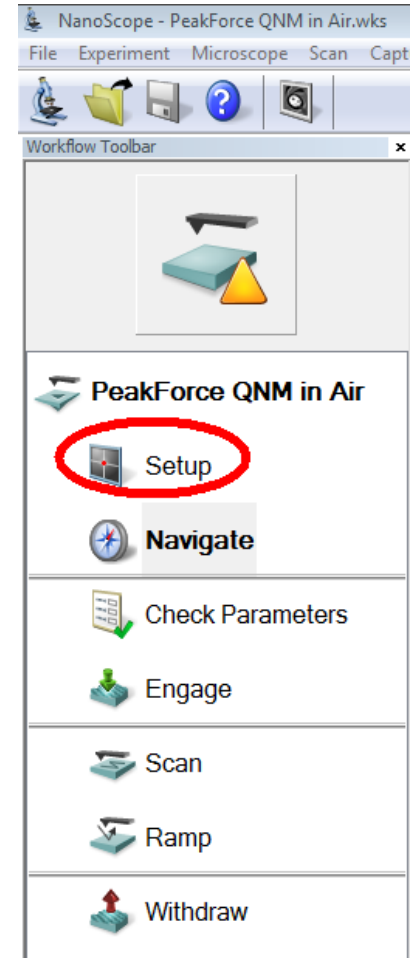
# Agenda

- Change of Cantilever
- What experiment/workspace to use
- How to optimize your scan
- Change of standard probe?
- Booking rules
- High Aspect Ratio Scanning
- QNM
- How to get SPIP software

# Change of Cantilever

- When changing cantilever – please remember to be in **setup**
- When do you need to change cantilever:
  - If the cantilever has broken off (please through it away)
  - If it does not help to adjust the scanning parameters and it does not help to clean\* the tip. (Then please through it away)
  - If you can see that the tip shape is not good enough for your purpose. (please save it)

\* Clean a tip by scanning on a carbon pad, mounted on a disc or a wafer. This only works in PeakForce tapping mode (or QNM).



# What experiment/workspace to use

- For standard experiment we recommend:
  - PeakForce QNM in air**
    - This includes ScanAsyst
    - And mapping of
      - Youngs modulus
      - Adhesion
      - Deformation
      - Dissipation
    - And this experiment is set up with good engage settings.
- No change in recommendation when using tapping mode.



Select Experiment: Dimension Icon

1 Select From:

Use previous experiment  
PeakForce QNM in Air - 05/23/14 | 02:33

Or

Choose an Experiment Category:

ScanAsyst Tapping Mode Contact Mode  
Electrical & Magnetic Mechanical Properties Other SPM

2 Select Experiment Group:

Force Modulation  
Force Volume  
Quantitative Nanomechanical Mapping

3 Select Experiment:

PeakForce QNM in Air  
PeakForce QNM in Air (Large Amplitude)  
PeakForce QNM in Air (Standard Amplitude)  
PeakForce QNM in Fluid  
PeakForce QNM in Fluid (Large Amplitude)  
PeakForce QNM in Fluid (Standard Amplitude)

Microscope: Dimension Icon

>> Change Scanner  
>> Change Microscope Setup

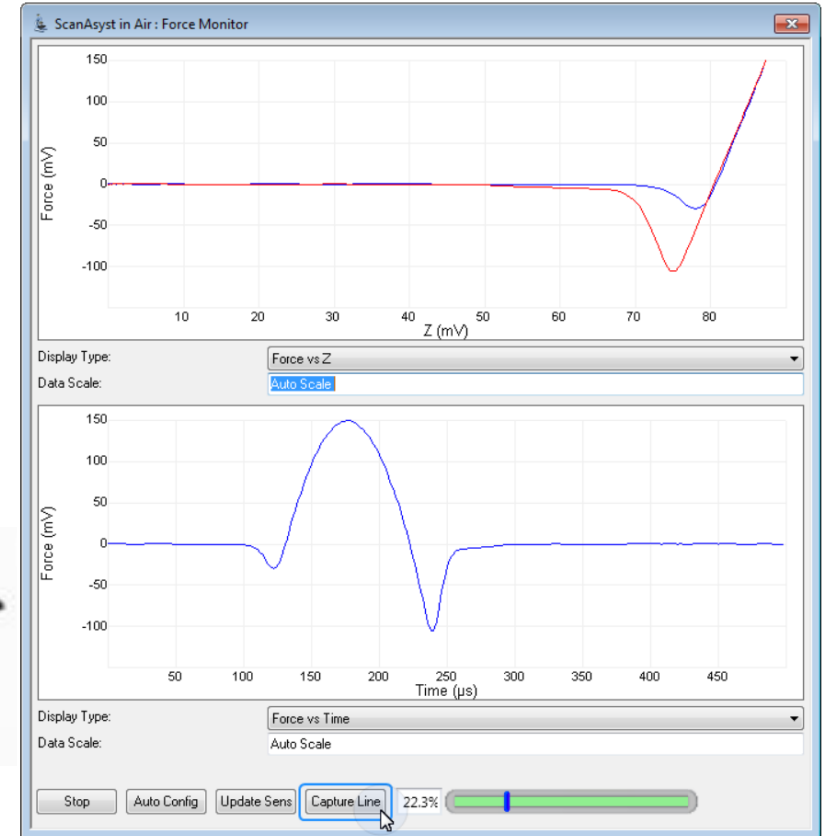
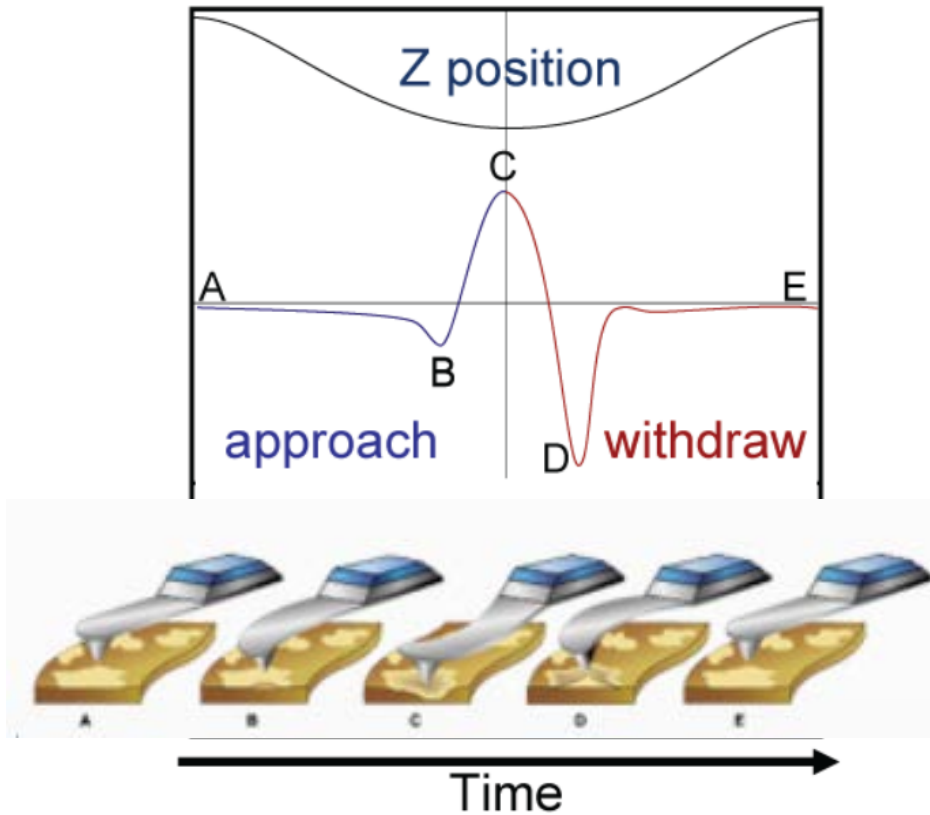
Experiment Description

PeakForce QNM™ is a groundbreaking atomic force microscope (AFM) imaging mode that provides AFM researchers unprecedented capability to quantitatively characterize nanoscale materials. It maps and distinguishes between nanomechanical properties, including modulus and adhesion, while simultaneously imaging sample topography at high resolution. PeakForce QNM operates over an extremely wide range, approximately 1 MPa to 50 GPa for modulus and 10 pN to 10 μN for adhesion, enabling characterization of a large variety of sample types.

Because it's based on Bruker's new proprietary Peak Force Tapping™ technology, the forces applied to the sample are precisely controlled and a variety of probes can be used. This allows indentations to be limited to several nanometers in most cases, which both maintains resolution

Cancel  Ignore Probe Parameters Load Experiment

# PeakForce Tapping – how to optimize scan



**Figure 1:** The “heartbeat.” Z position, Force and Current as a function of time during one Peak Force Tapping cycle. Blue indicates approach while red indicates retract.

**Scan**

- Scan Size: 500 nm
- Aspect Ratio: 1.00
- X Offset: 0.000 nm
- Y Offset: 0.000 nm
- Scan Angle: 0.00 °
- Scan Rate: 0.977 Hz
- Samples/Line: 512

**Feedback**

- Feedback Gain: 36.75
- Peak Force Setpoint: 0.3379 V
- ScanAsyst Auto Control: On

**Peak Force Tapping Control**

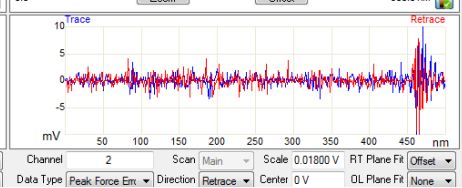
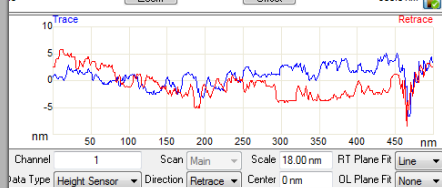
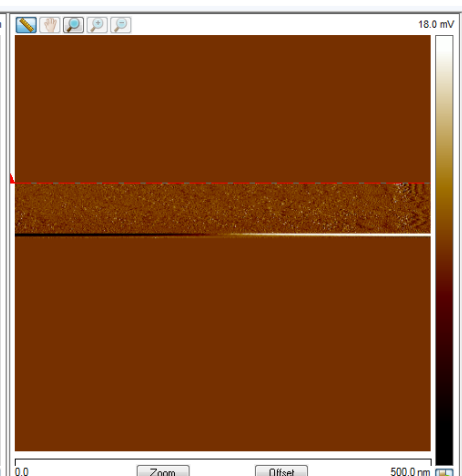
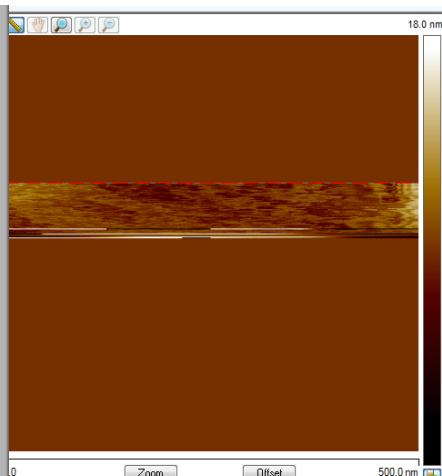
- Peak Force Amplitude: 150 nm
- Peak Force Frequency: 2 KHz
- Lift Height: 295 nm
- Sync Distance QNM: 81.41
- Adhesion Algorithm: Threshold Cross...

**Cantilever Parameters**

- Spring Constant: 0.4000 N/m
- Tip Radius: 5.00 nm
- Tip Half Angle: 18.0 °

**PF Mapping Limits**

**Limits**



**Scan**

- Scan Size: 3.00 μm
- Aspect Ratio: 1.00
- X Offset: 0.000 nm
- Y Offset: 0.000 nm
- Scan Angle: 0.00 °
- Scan Rate: 0.977 Hz
- Samples/Line: 256

**Feedback**

- Feedback Gain: 16.83
- Peak Force Setpoint: 0.2205 V
- ScanAsyst Auto Control: Individual
- ScanAsyst Auto Gain: On
- ScanAsyst Auto Setpoint: On
- ScanAsyst Auto Scan Rate: On
- ScanAsyst Auto Z Limit: On

**Peak Force Tapping Control**

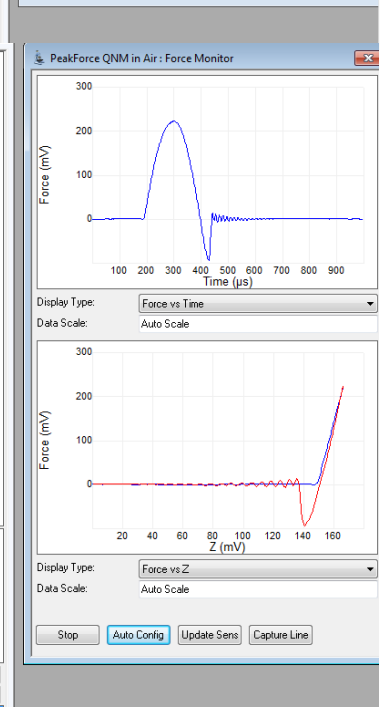
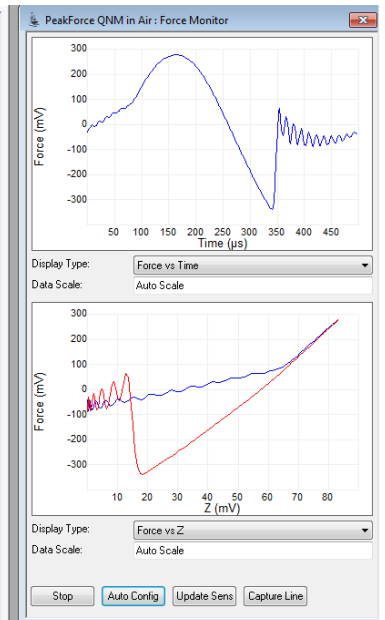
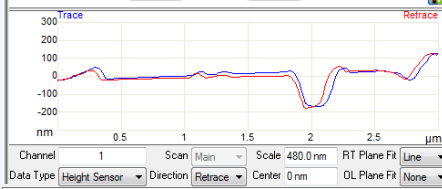
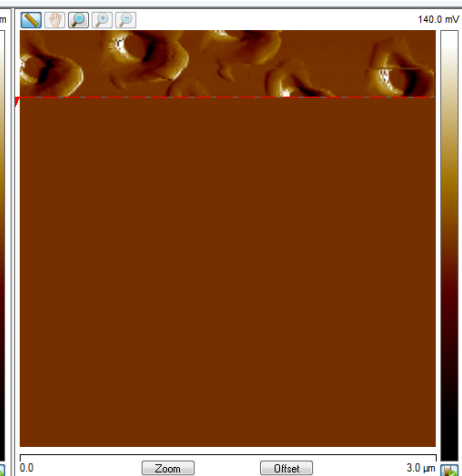
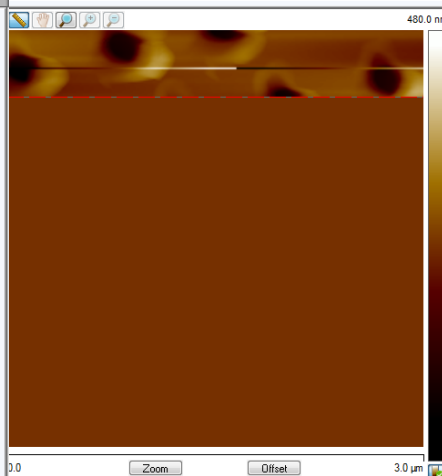
- Peak Force Amplitude: 300 nm
- Peak Force Frequency: 1 KHz
- Lift Height: 243 nm
- Sync Distance QNM: 147.8
- Adhesion Algorithm: Threshold Crossing

**Cantilever Parameters**

- Spring Constant: 0.4000 N/m
- Tip Radius: 5.00 nm
- Tip Half Angle: 18.0 °

**PF Mapping Limits**

**Limits**



# How to optimize your scan

- Look at the **force curves** to make sure they look good.
- Adjust **Peak Force amplitude**. High value helps to release the tip from the surface.
- **Peak Force Frequency**: it some times help to set it down to 1KHz
- **Feedback gain**: Increasing the feedback gain can improve surface tracking; but too high a gain value will cause oscillation of the system and increase noise.
- **Peak Force Setpoint**: Increasing the Peak Force Setpoint will increase the interaction force between tip and sample which will result in good surface tracking but risks damaging the tip or the sample. It is generally desirable to reduce the Peak Force Setpoint to as small a value as possible.
- **Auto Config**: Press *Auto Config* if the force curve looks like this:

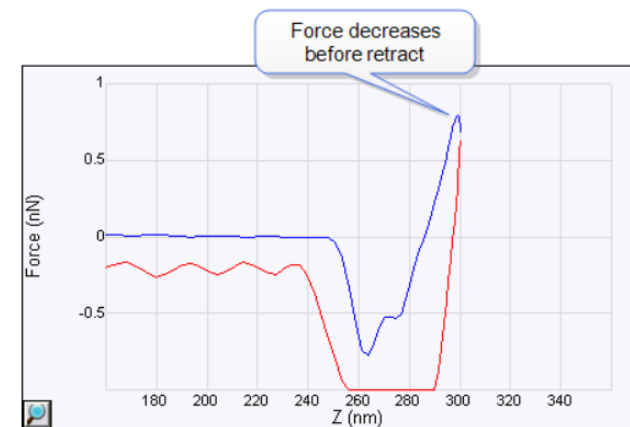
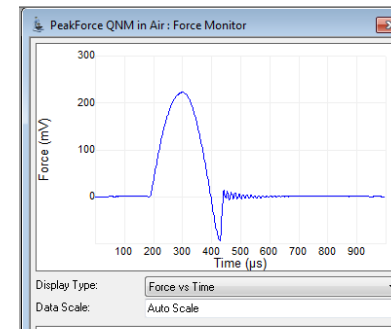


Figure 2: ScanAsyst Late Synch

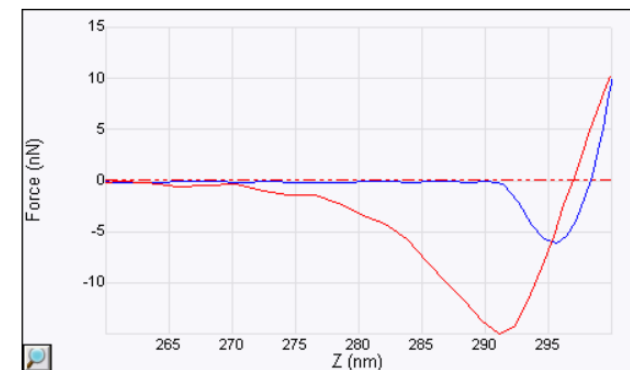
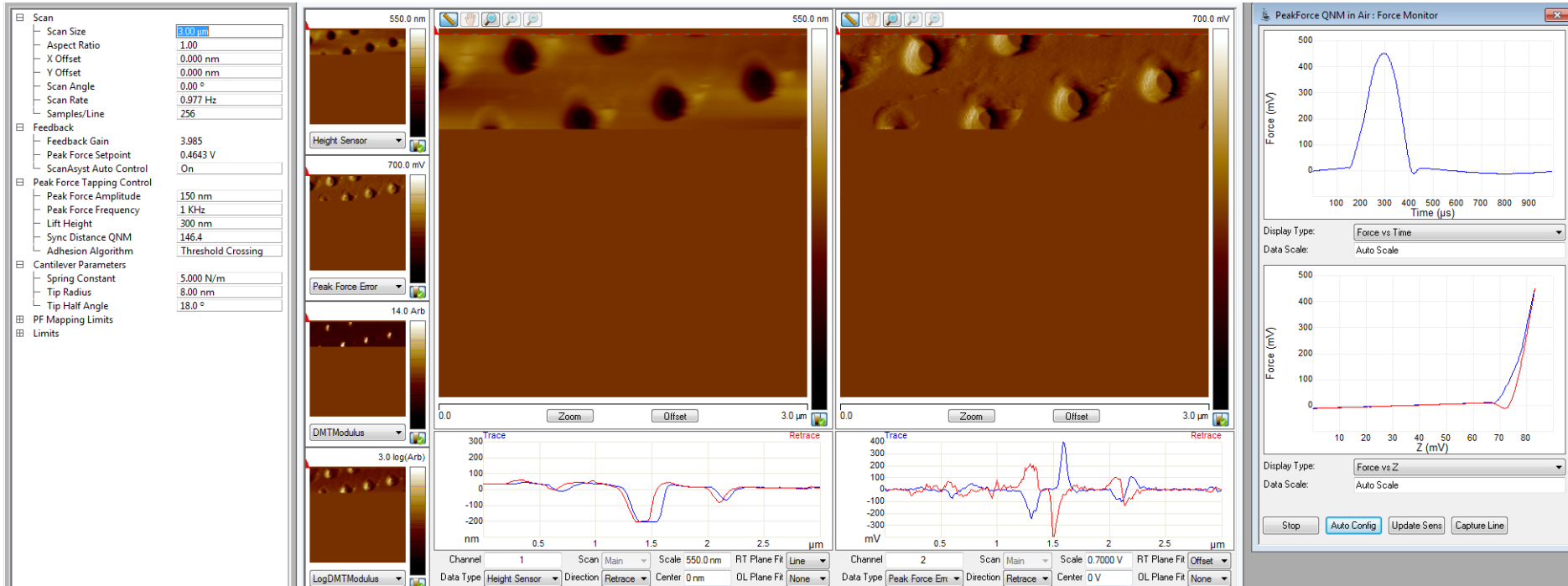


Figure 3: ScanAsyst Early Synch: the retract curve (red) should not be to the left of the (blue) approach curve.

# Change of standard probe?



Here I used a stiffer probe: I have not adjusted any parameters (except scan size)

TAP150A:  $k=5\text{N/m}$

ScanAsyst in air:  $k=0.4\text{N/m}$

We are considering changing to this probe



## Booking rules

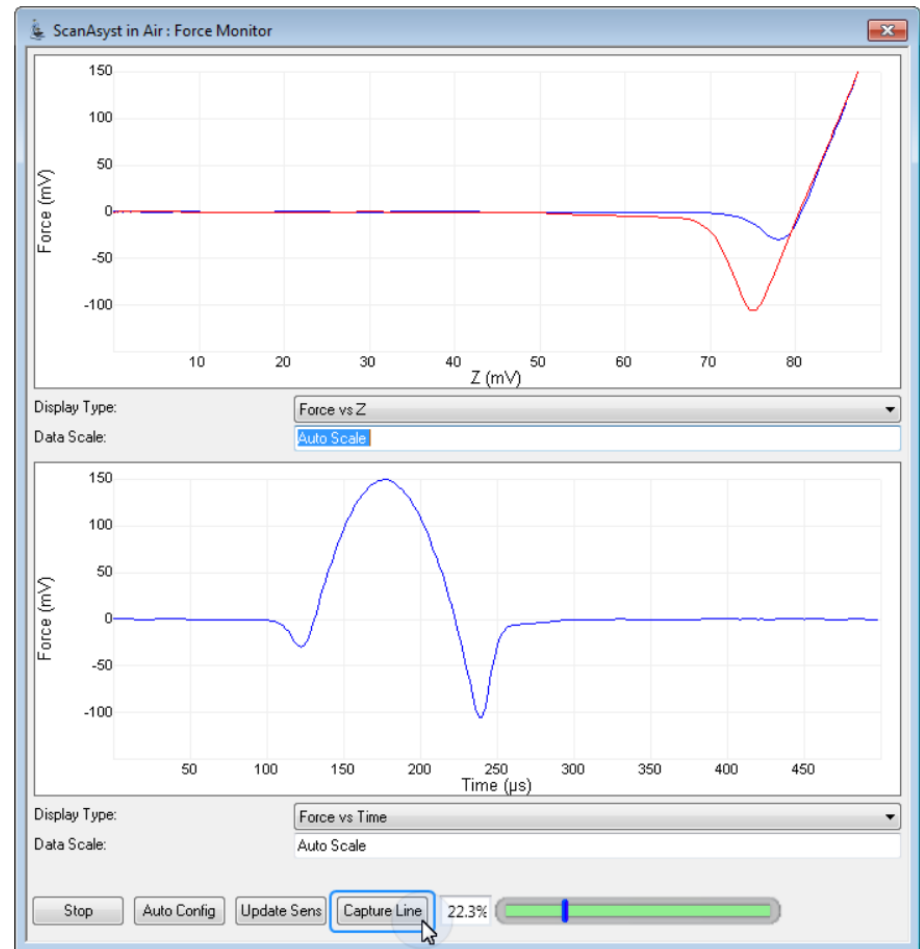
- We will keep the current booking rules: Monday to Friday between 8am and 4 pm
  - Maksimum 2 hours of booking per user.
  - 15min delay => your booking is lost

## High Aspect Ratio (HAR) scanning

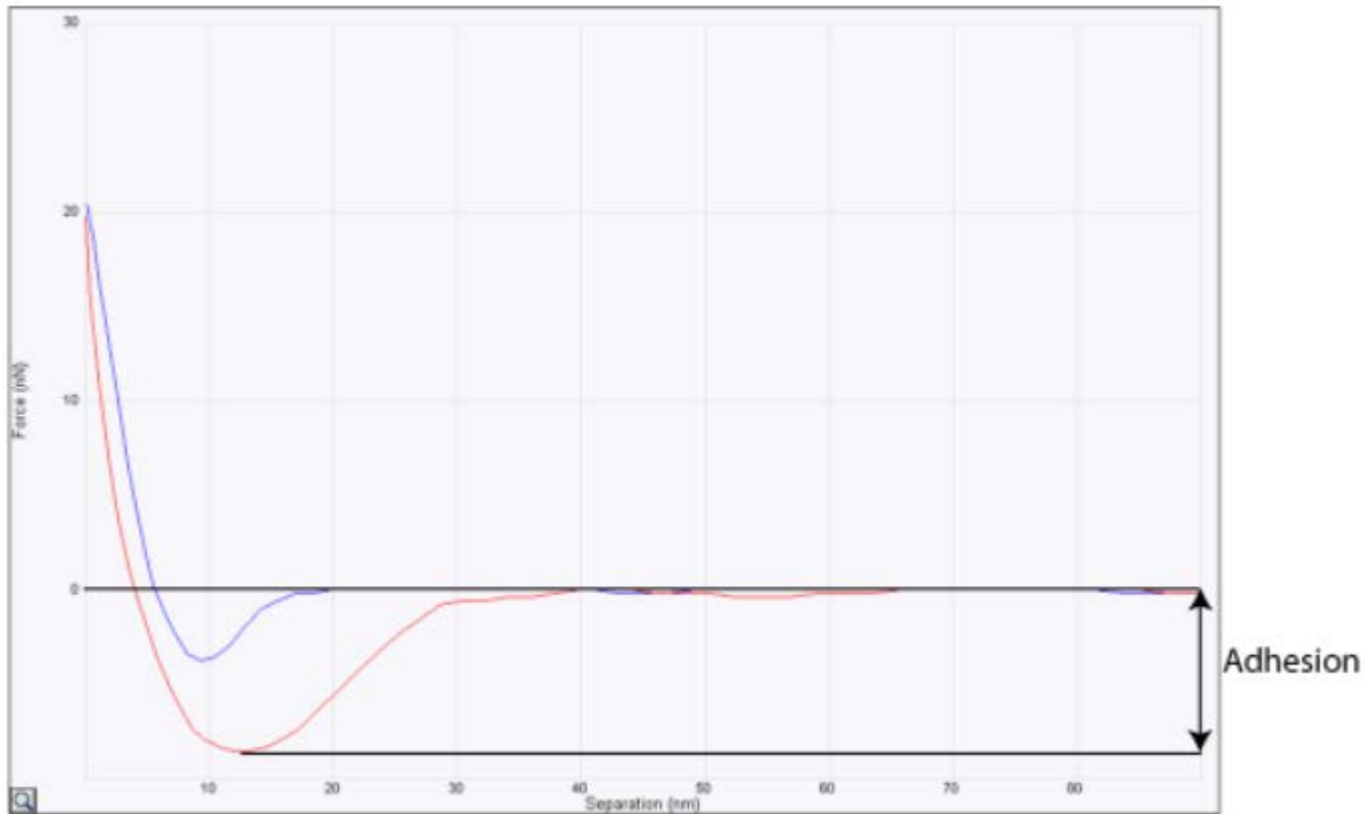
- Right now use dedicated Tapping mode experiments/workspaces
  - TappingMode 300nm trench (small step)
  - Tapping mode in air – 6 $\mu$ m Deep Trench (deep steps)
- Always engage with 0nm scan size and integral gain low ( $\sim 0.5$ )
- Increase gain and scan size very slowly: 10nm- > 50nm- > 100nm- > 1 $\mu$ m
- If you get a false low depth you may have to decrease the amplitude setpoint a little.
- Using PeakForce tapping – maybe in the future

# Quantitative Nanomechanical Mapping (QNM)

- Mapping of
  - Youngs Modulus
  - Adhesion
  - Deformation
  - Dissipation

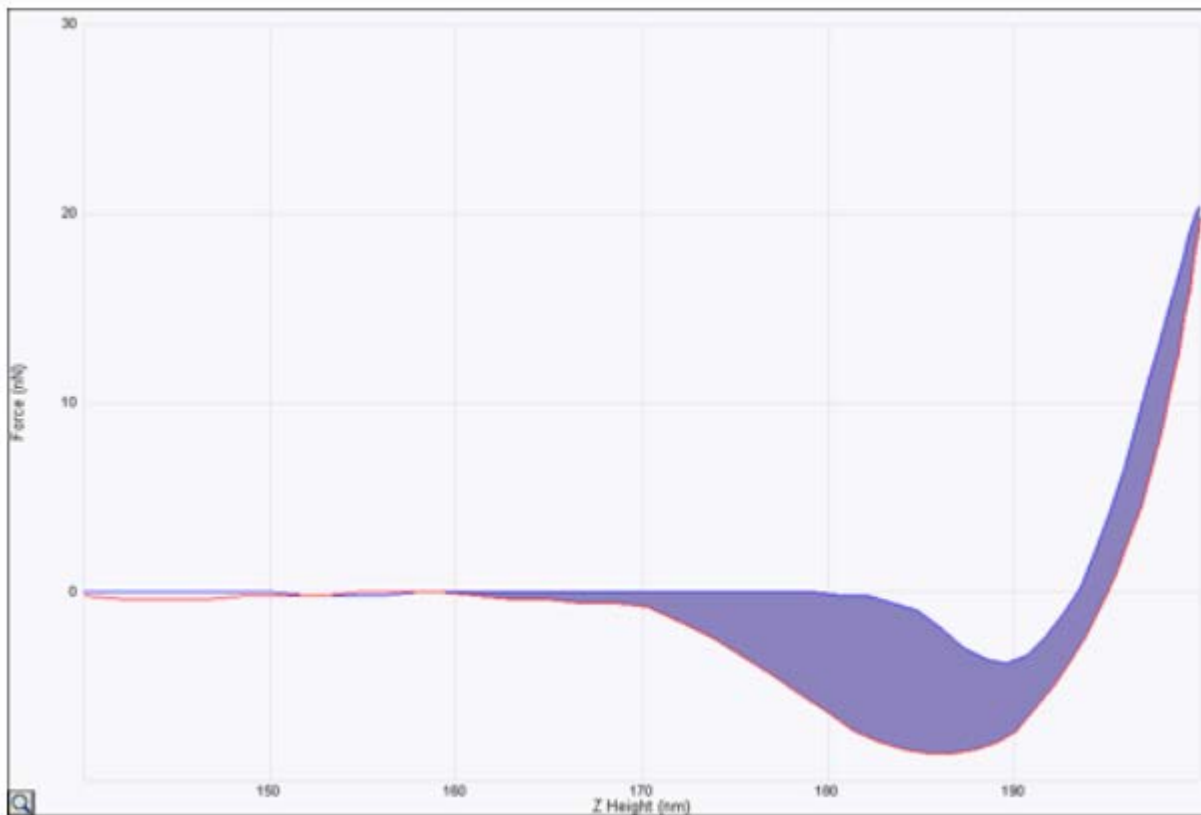


# Adhesion

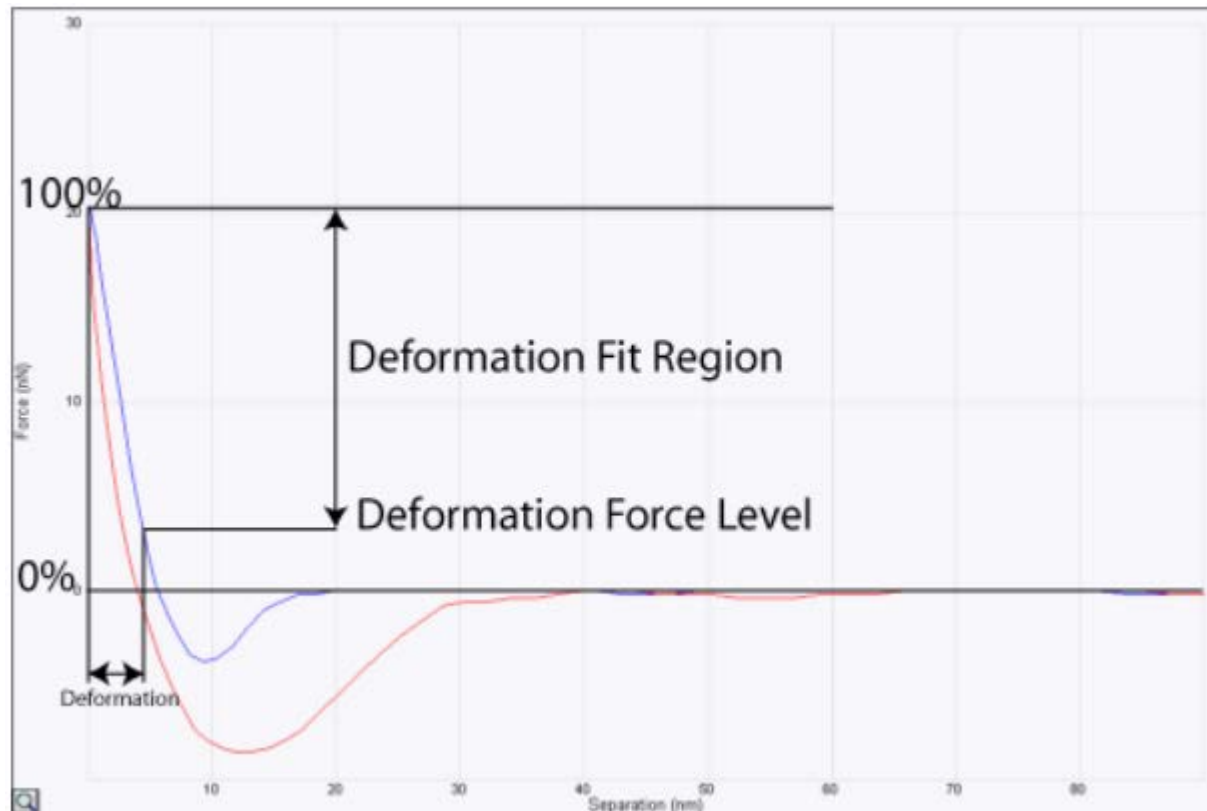


# Energy dissipation

- Mechanical energy loss pr. tapping cycle
- Elastic deformation has low dissipation



# Deformation – maximum deformation of the sample (actually a little less)



# The reduced Young's Modulus

- DMT Modulus for hard materials
- Sneddon Modulus for soft materials (like cells ...)

The reduced Young's Modulus,  $E^*$ , is obtained by fitting the retract curve (green line in Figure 1) using the Derjaguin, Muller, Toropov (DMT)<sup>1</sup> model given by

$$F_{tip} = \frac{4}{3}E^* \sqrt{Rd^3} + F_{adh}$$

Where  $F_{tip}$  is the force on the tip,  $F_{adh}$  is the adhesion force,  $R$  is the tip end radius and  $d$  is the tip-sample separation.

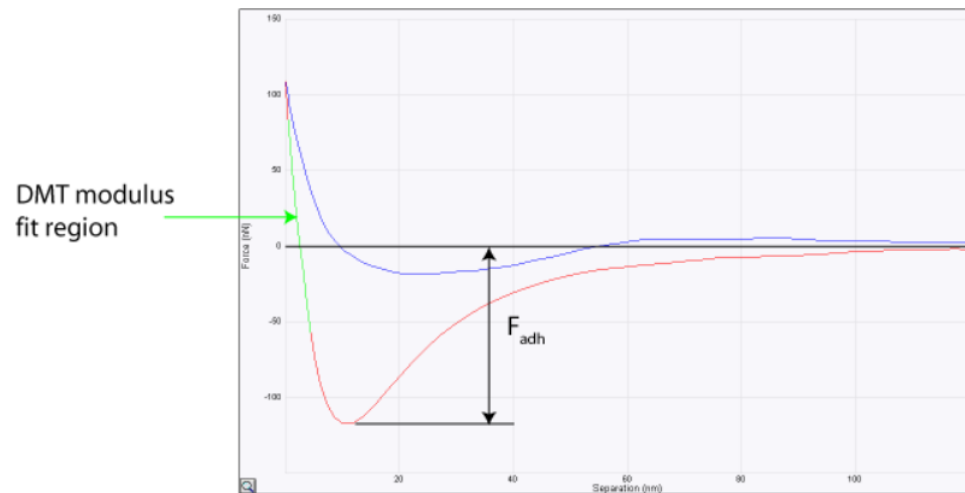


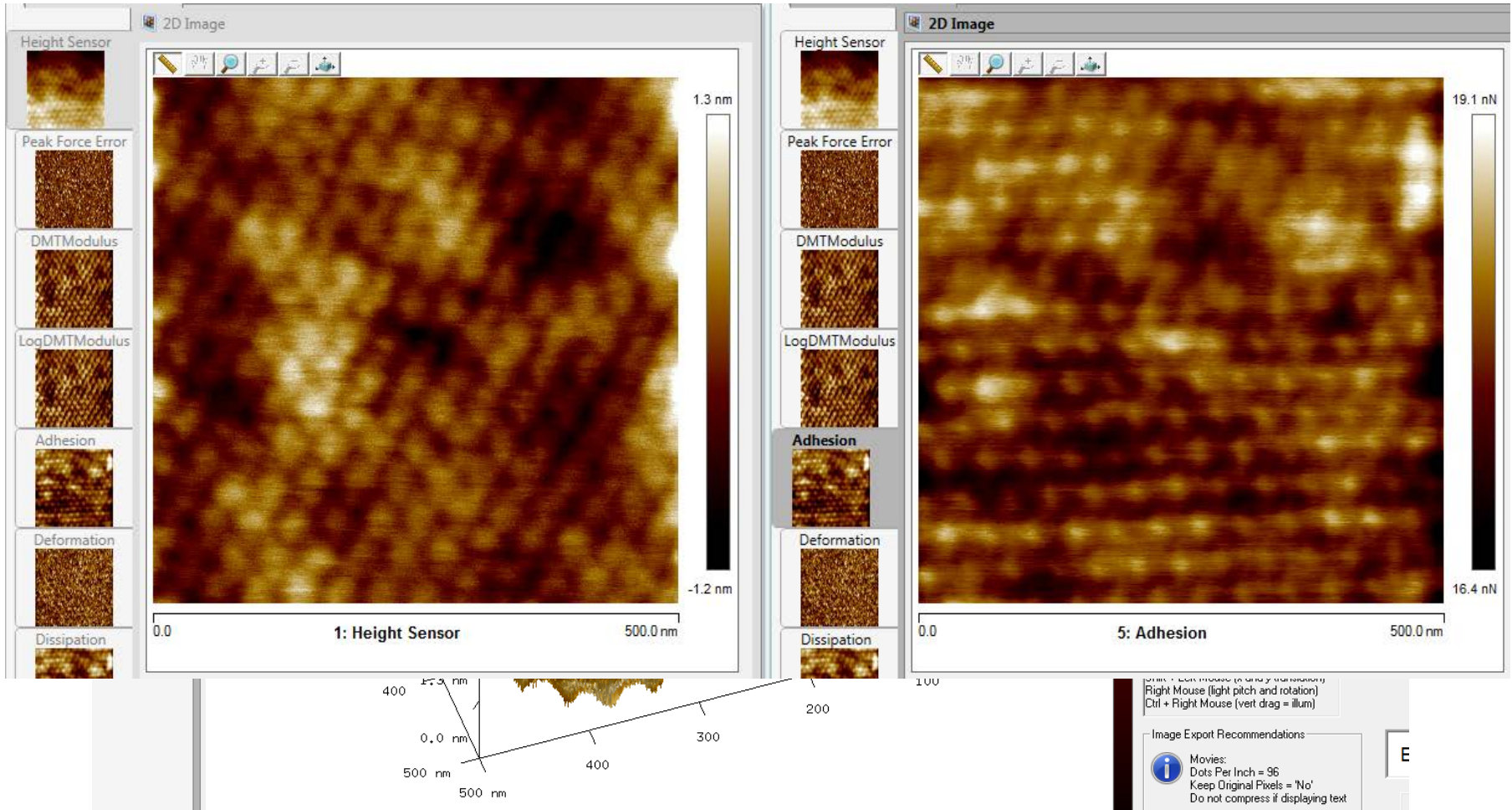
Figure 1: Force vs. Separation plot

## How to use QNM

- By using the QNM workspace you get qualitatively mapping of *adhesion*, *dissipation*, *deformation* and *moduls*. That can give you a material contrast in the image that is not in the height data.
- For quantitative values for the *adheision*, *dissipation*, *deformation* and *moduls* you need to calibrate the system for the tip in use. We have a procedure for this, we have seen it once. Let us know if you want to do this and we can try it out together.



# Example: mix of two different polymers with different adhesion. *By courtesy of Tao Li*



# SPIP license

- DTU has a site licens – the following institutes have joined
  - Nanotech
  - Physics
  - Chemistry
  - Mechanics
  - CEN
  - Danchip
  - Energikonvertering
- To get it:
  - Contact John Tandrup Riedel [JOTRI@ADM.DTU.DK](mailto:JOTRI@ADM.DTU.DK)
  - He needs name, email and institute

# The End